

2nd Mexican Workshop on Additive Manufacturing & 3D Printing: From Aerospace to the Printing

2nd-4th June, 2015 Querétaro, México

**Tecnológico de Monterrey**

## Reverse Engineering Methodology for Free Form Components and Internal Features

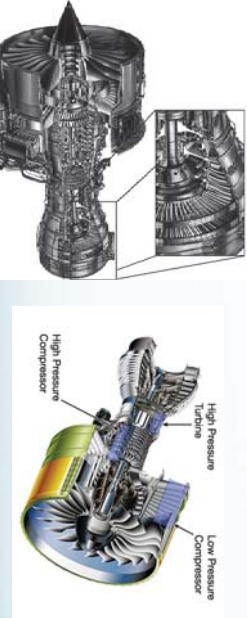
-Aerospace Applications-

Dr. Héctor R. Siller\*

Escuela de Ingeniería y Ciencias Tecnológico de Monterrey

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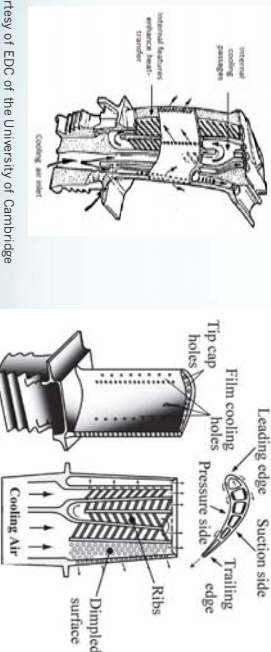
## Common aeronautic components difficult to cut



Courtesy of Rolls Royce UTC at the University of Nottingham

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## Internal geometric features in aeronautic components



Courtesy of EDC of the University of Cambridge

Courtesy of Tokyo University of A&T Thermal Fluids Engineering Lab

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## Properties of Nickel Alloys

- Melting Temp. 1455°C unalloyed
- Young Modulus ~ 240Gpa (Steel 210 Gpa)
- Density 8.9 g/cc (steel 7.8 g/cc)
- Tensile Strength 100-1410 Mpa

**Difficult for processing**  
**Low Machinability**



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# Reverse Engineering for Aeronautic Components

*"Producing a copy of the original part in order to generate a reconstructed 3D model"*

### Used for:

- Conceptual and functional design.
- Rapid maintenance operations.
- CAD/CAM/CAE

### Advantages:

- Generation of 3D models when blue-prints are not available.
- Reduction of reconstruction time of 3D models (1/3 of time used with blue prints)

# Metrology techniques for RE

| Part dimensions      | Laser tracker | Direct Comparison | Tactile CMM | Optical CMM | X-ray tomography | Fringe projection | Fringe reflection / Deflectometry | Photogrammetry | Interferometry | Tactile Surface topography & Profilometry | Optical Surface topography & Profilometry | Confocal Microscopy | Scanning Force Microscopy |
|----------------------|---------------|-------------------|-------------|-------------|------------------|-------------------|-----------------------------------|----------------|----------------|-------------------------------------------|-------------------------------------------|---------------------|---------------------------|
| Large                | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Medium               | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Small                | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Shape complexity     | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Low                  | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| High                 | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Material and surface | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Black oxidation      | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Aluminum             | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Stainless steel      | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Carbon steel         | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Other                | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Transparency         | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Legend               | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |
| Not suitable         | ●             | ●                 | ●           | ●           | ●                | ●                 | ●                                 | ●              | ●              | ●                                         | ●                                         | ●                   | ●                         |



Courtesy of Faro

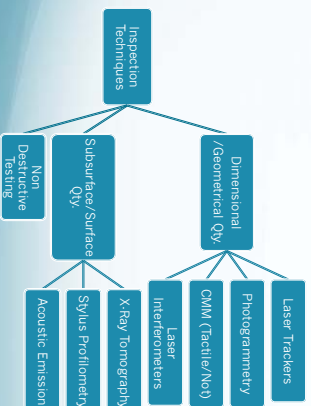
# Reverse Engineering for Aeronautic Components

- Common Specifications of Aeronautic Components, suitable for RE
- Tight tolerances.
- Freeform surfaces.
- Extreme working conditions (1,500 C)
- Internal cooling blades (1,000 C)



Courtesy of Honeywell Aerospace Chihuahua

# Metrology Techniques for RE



Arahata, K., Silver, H. R., De Chirio, L., Rodriguez, C. A., & Cantatore, A. (2012). Metrology of freeform surfaces. *International Journal of Metrology and Quality Engineering*, 3(01), 55-62

## Permissible Errors and Costs

| Size        | Machine and subsystem (rough)             | CMM cost and MPE (100µm)              | Photogrammetry cost and MPE (50µm and 10µm) |
|-------------|-------------------------------------------|---------------------------------------|---------------------------------------------|
| Extra large | Fixed and moving structures<br>10000 mm   | 750000 USD<br>100µm (volumetric) [11] | 230000 USD<br>400µm [12]                    |
| Large       | Skin panel section 1000 mm                | 680000 USD<br>90µm (volumetric) [13]  | 230000 USD<br>300µm [12]                    |
| Meso scale  | Carbon backpack (direct blades)<br>750 mm | 365000 USD<br>4µm [14]                | 200000 USD<br>50µm [12]                     |
|             | Turbine blades<br>500 mm                  | 98055 USD<br>4µm [16]                 | 159000 USD<br>20µm [12]                     |
| Microscale  | MK66 rocket nozzle<br>70 mm               | 98055 USD<br>3µm [16]                 | 160000 USD<br>10µm [12]                     |
|             |                                           |                                       | 240000 USD<br>5µm [17]                      |



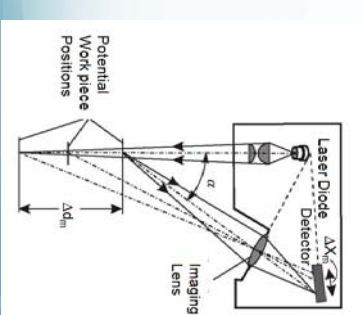
Courtesy of Faro

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Aamuhla, K., Silver, H. R., De Chiffre, L., Rodriguez, C. A., & Camarero, A. (2012). Evaluation of metrology technologies for free form surfaces. *International Journal of Metrology and Quality Engineering*, 3(01), 55-62.

## Optical Scanner

- Advantages
  - Fast data acquisition when compared with CMM (200pts/s vs 25.000 pts/s)
- Disadvantages
  - Issues with accuracy/uncertainty
  - Workpiece preparation (3-5µm coating)



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## Coordinate Measuring Machine

- Advantages
  - Reliable Inspection with well known standards
  - Low Uncertainty
  - High Traceability
- Disadvantages
  - Tactile sensitivity
  - Rigid components
  - Low productivity

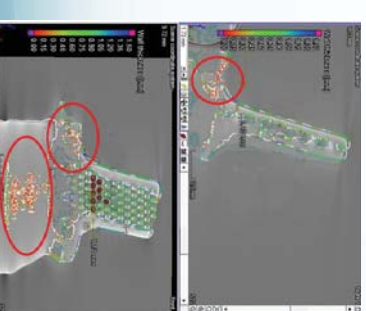


Courtesy of Carl Zeiss

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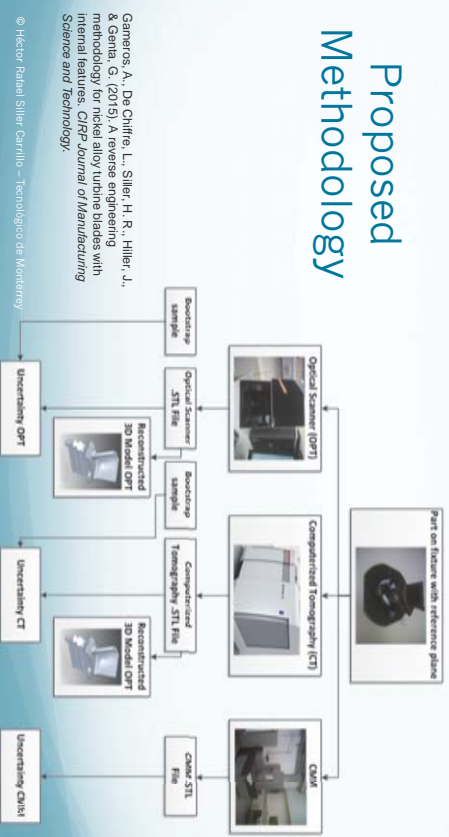
## Computerized Tomography (CT)

- Advantages
  - Internal features reconstruction
  - Non Destructive Internal Inspection
- Disadvantages
  - Dispersion/Beam hardening
  - Lack of international standards.



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## Proposed Methodology

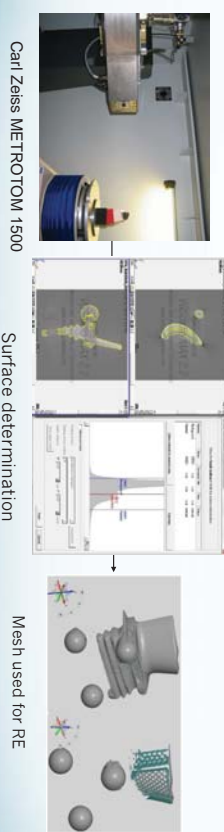


Generato, A., De Chiffra, L., Siller, H. R., Hiller, J., & Gerda, G. (2015). A reverse engineering methodology for CIPF sintered blades with internal features. *Journal of Manufacturing Science and Technology*.

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## Experimental Procedure

- CT Scanner



Carl Zeiss METROTOM 1500

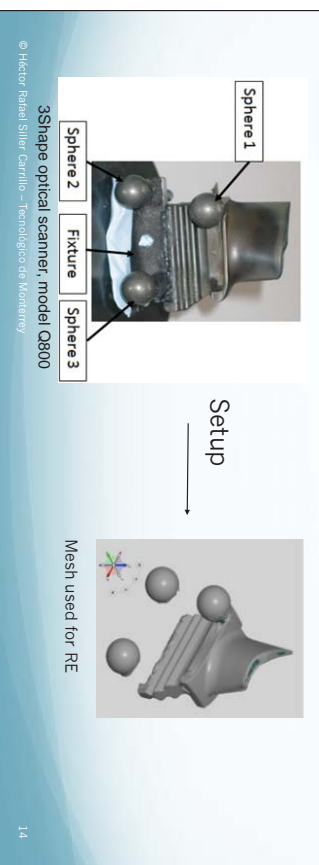
Surface determination

Mesh used for RE

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## Experimental Procedure

- Optical Scanner



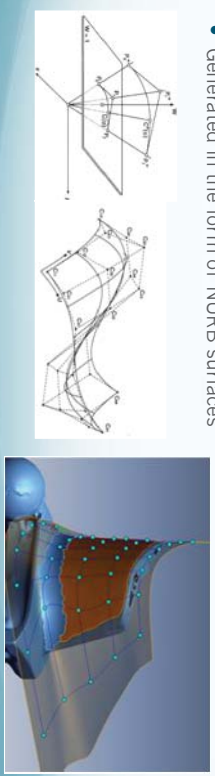
3Shape optical scanner, model Q800

Mesh used for RE

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## Experimental Procedure

- Point triangulation (\*stl)
- Numerical representation
- Construction of analytical equations (Bilinear surface elements)
- Generated in the form of NURB surfaces



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## Experimental Procedure

- Uncertainty Evaluation
- Use of CMM measurements as reference
- Use of Modular Freeform Gage for reference uncertainty

| Uncertainty Component | Symbol    | Type | Estimation                |
|-----------------------|-----------|------|---------------------------|
| MFG Uncertainty       | $U_{MFG}$ | A    | MFG Uncertainty           |
| Repeatability         | $U_{CMM}$ | A    | Repeated CMM measurements |
| Temperature           | $U_T$     | B    | U-shaped distribution     |

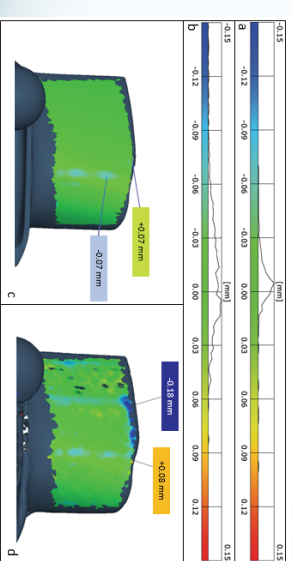
$$U_{MFG} = k \sqrt{U_{MFG}^2 + U_{CMM}^2 + U_T^2}$$

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## Results and discussion



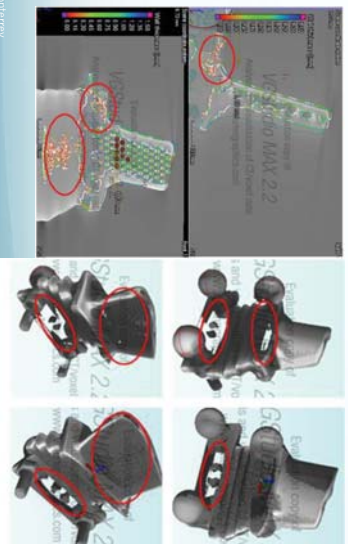
Comparison of deviations values from CMM measurements and optical scanner (a and c) and comparison between CMM and CT scans (b and d).

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## Results and discussion

- Dispersion of measurements in CT
- Use of aluminum box for filtering x-ray beam.
- Surface determination procedure in 2 stages.
- Part internal porosity



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## Results and discussion

- Uncertainty estimation for MFG (Values in µm)

| Uncertainty Component                                   | Type | Estimation               | Standard uncertainty |
|---------------------------------------------------------|------|--------------------------|----------------------|
| Calibration uncertainty of single objects               | B    | Calibration certificates | 0.90                 |
| Uncertainty of the relative positions                   | A    | CMM measurements         | 5.51                 |
| <b>Combined standard uncertainty</b>                    |      |                          | <b>5.58</b>          |
| <b>Expanded Uncertainty (k=2), <math>U_{MFG}</math></b> |      |                          | <b>11.16</b>         |

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## Results and discussion

- Uncertainty estimation for CMM (Values in  $\mu\text{m}$ )

| Component                                                | Type | Estimation                | Standard uncertainty |
|----------------------------------------------------------|------|---------------------------|----------------------|
| MFG Uncertainty                                          | A    | MFG Uncertainty           | 5.58                 |
| Repeatability                                            | A    | Repeated CMM measurements | 6.97                 |
| Temperature                                              | B    | U-shaped distribution     | 0.23                 |
| <b>Combined standard uncertainty</b>                     |      |                           | <b>8.93</b>          |
| <b>Expanded Uncertainty (k=2), <math>U_{95\%}</math></b> |      |                           | <b>17.86</b>         |

## Results and discussion

- Uncertainty estimation for CT scanner (values in  $\mu\text{m}$ ).

| Component                                                | Type | Estimation                  | Standard uncertainty |
|----------------------------------------------------------|------|-----------------------------|----------------------|
| Reference uncertainty                                    | A    | Reference uncertainty (CMM) | 8.93                 |
| Repeatability                                            | A    | Bootstrap method            | 58.93                |
| Temperature                                              | B    | U-shaped distribution       | 0.14                 |
| <b>Combined standard uncertainty</b>                     |      |                             | <b>59.60</b>         |
| <b>Expanded Uncertainty (k=2), <math>U_{95\%}</math></b> |      |                             | <b>119.20</b>        |

## Results and discussion

- Uncertainty estimation for optical scanner (values in  $\mu\text{m}$ ).

| Uncertainty Component                                    | Type | Estimation                  | Standard uncertainty |
|----------------------------------------------------------|------|-----------------------------|----------------------|
| Reference uncertainty                                    | A    | Reference uncertainty (CMM) | 8.93                 |
| Repeatability                                            | A    | Bootstrap method            | 19.92                |
| Temperature                                              | B    | U-shaped distribution       | 1.37                 |
| <b>Combined standard uncertainty</b>                     |      |                             | <b>21.87</b>         |
| <b>Expanded Uncertainty (k=2), <math>U_{95\%}</math></b> |      |                             | <b>43.70</b>         |

## Results and discussion

- Deviation of final model
- Deviation in the range of  $\pm 50 \mu\text{m}$ .
- Sporadic Deviations in the range of  $\pm 780 \mu\text{m}$ .



## Conclusions

- Total time for reconstruction: 45 hours (1/3 of reconstruction from blueprints)
- Is not recommendable to use the CT scans for the geometrical reconstruction of the external surface (Bigger uncertainty; poorer precision)
- The combination of Optical Scanner and CT Scanner for RE is very promising for the Additive Manufacturing of Aeronautic Components and freeform shapes with internal features



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Investigación que Transforma Vidas

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CONACYT

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